



ILIM-P, Load simulation for specimen current injection

Product description

The device is used for load simulation with adjustable current limitation in the current imprinting.

It has 15 independent channels with common external supply and can be integrated into external test systems via the serial interface.
An inductive load component can be switched on separately per channel.

Field of application

Research & Development, Life cycle testing, In-line testing, End of line testing



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Technical data

Test bench/device <ul style="list-style-type: none"> Modular design in 19"/3 HU rack mountable housing Mounting for 1x supply/control unit and 5 load modules 3 load channels with current limitation in the positive load path to supply negative switching loads Integrated debouncing circuit 400 ms per channel For higher currents, a parallel connection of several channels is possible 	
Software <ul style="list-style-type: none"> Firmware auf microcontroller pic <ul style="list-style-type: none"> - Control load simulation, debouncing, serial interface on/off per channel - Up to 10 load boxes I-LIM-P / I-LIM-N and ELA can be cascaded in a compound 	
Scope of testing <ul style="list-style-type: none"> 15x current imprinting 0 to 1000 mA Output voltage range 0 to 28 V Supply via external DC power supply unit (max. 30 V, max. 15 A) (common to all 15 channels) Inductive load component of 50 μH can be switched on per channel 	
Input-/visualisation units <ul style="list-style-type: none"> 15x digital locking potentiometer, 3 digit Setting 0 – 999 mA in 1 mA steps 15x self-test button 15x switching on inductive load component 	Dimensions/Transport <ul style="list-style-type: none"> 490x266x300 mm (WxHxD)
Test time <ul style="list-style-type: none"> Setting time < 50 μs 	Exemplary device type <ul style="list-style-type: none"> 071 0796